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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	20 ns
/oltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	24
lumber of Macrocells	64
lumber of Gates	4000
lumber of I/O	48
perating Temperature	0°C ~ 70°C (TA)
Nounting Type	Surface Mount
Package / Case	68-LCC (J-Lead)
Supplier Device Package	68-PLCC (24.23x24.23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/isplsi-1024-60lj

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



ispLSI[®] 1024 Device Datasheet

June 2010

All Devices Discontinued!

Product Change Notification (PCN) #09-10 has been issued to discontinue all devices in this data sheet.

The original datasheet pages have not been modified and do not reflect those changes. Please refer to the table below for reference PCN and current product status.

Product Line	Ordering Part Number	Product Status	Reference PCN
	ispLSI 1024-60LJ		
	ispLSI 1024-80LJ		
	ispLSI 1024-90LJ		
ispLSI 1024	ispLSI 1024-60LJI	Discontinued	PCN#09-10
15pL3i 1024	ispLSI 1024-60LT	Discontinued	PCN#09-10
	ispLSI 1024-80LT		
	ispLSI 1024-90LT		
	ispLSI 1024-60LTI		



ispLSI® 1024

In-System Programmable High Density PLD

Features

• HIGH-DENSITY PROGRAMMABLE LOGIC

- High-Speed Global Interconnect
- 4000 PLD Gates
- 48 I/O Pins, Six Dedicated Inputs
- 144 Registers
- Wide Input Gating for Fast Counters, State Machines, Address Decoders, etc.
- Small Logic Block Size for Fast Random Logic
- Security Cell Prevents Unauthorized Copying

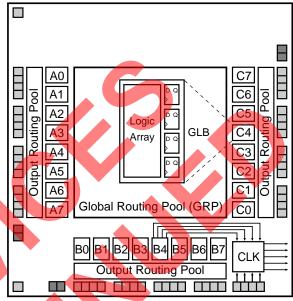
• HIGH PERFORMANCE E2CMOS® TECHNOLOGY

- fmax = 90 MHz Maximum Operating Frequency
- fmax = 60 MHz for Industrial and Military/883 Devices
- tpd = 12 ns Propagation Delay
- TTL Compatible Inputs and Outputs
- Electrically Erasable and Reprogrammable
- Non-Volatile E²CMOS Technology
- 100% Tested

• IN-SYSTEM PROGRAMMABLE

- In-System Programmable™ (ISP™) 5-Volt Only
- Increased Manufacturing Yields, Reduced Time-to-Market, and Improved Product Quality
- Reprogram Soldered Devices for Faster Debugging
- COMBINES EASE OF USE AND THE FAST SYSTEM SPEED OF PLDs WITH THE DENSITY AND FLEX-IBILITY OF FIELD PROGRAMMABLE GATE ARRAYS
- Complete Programmable Device Can Combine Glue Logic and Structured Designs
- Four Dedicated Clock Input Pins
- Synchronous and Asynchronous Clocks
- Flexible Pin Placement
- Optimized Global Routing Pool Provides Global Interconnectivity
- ispDesignEXPERT™ LOGIC COMPILER AND COM-PLETE ISP DEVICE DESIGN SYSTEMS FROM HDL SYNTHESIS THROUGH IN-SYSTEM PROGRAMMING
- Superior Quality of Results
- Tightly Integrated with Leading CAE Vendor Tools
- Productivity Enhancing Timing Analyzer, Explore Tools, Timing Simulator and ispANALYZER™
- PC and UNIX Platforms

Functional Block Diagram



0139-A-isn

Description

The ispLSI 1024 is a High-Density Programmable Logic Device containing 144 Registers, 48 Universal I/O pins, six Dedicated Input pins, four Dedicated Clock Input pins and a Global Routing Pool (GRP). The GRP provides complete interconnectivity between all of these elements. The ispLSI 1024 features 5-Volt in-system programmability and in-system diagnostic capabilities. It is the first device which offers non-volatile reprogrammability of the logic, as well as the interconnect to provide truly reconfigurable systems.

The basic unit of logic on the ispLSI 1024 device is the Generic Logic Block (GLB). The GLBs are labeled A0, A1 .. C7 (see figure 1). There are a total of 24 GLBs in the ispLSI 1024 device. Each GLB has 18 inputs, a programmable AND/OR/XOR array, and four outputs which can be configured to be either combinatorial or registered. Inputs to the GLB come from the GRP and dedicated inputs. All of the GLB outputs are brought back into the GRP so that they can be connected to the inputs of any other GLB on the device.

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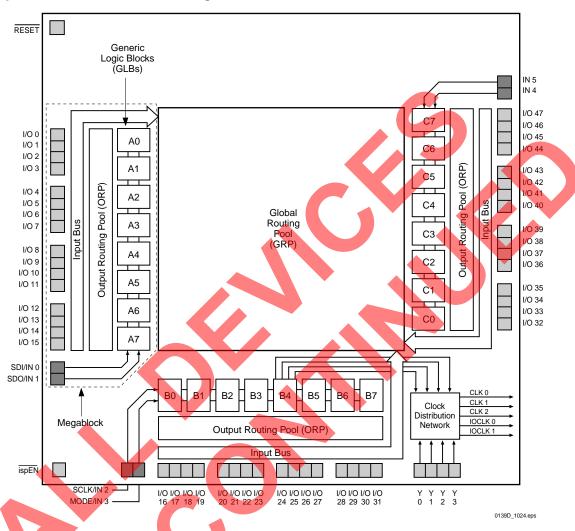
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1024_06



Functional Block Diagram

Figure 1.ispLSI 1024 Functional Block Diagram

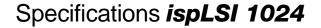


The device also has 48 I/O cells, each of which is directly connected to an I/O pin. Each I/O cell can be individually programmed to be a combinatorial input, registered input, latched input, output or bi-directional I/O pin with 3-state control. Additionally, all outputs are polarity selectable, active high or active low. The signal levels are TTL compatible voltages and the output drivers can source 4 mA or sink 8 mA.

Eight GLBs, 16 I/O cells, two dedicated inputs and one ORP are connected together to make a Megablock (see figure 1). The outputs of the eight GLBs are connected to a set of 16 universal I/O cells by the ORP. The I/O cells within the Megablock also share a common Output Enable (OE) signal. The ispLSI 1024 device contains three of these Megablocks.

The GRP has as its inputs the outputs from all of the GLBs and all of the inputs from the bi-directional I/O cells. All of these signals are made available to the inputs of the GLBs. Delays through the GRP have been equalized to minimize timing skew.

Clocks in the ispLSI 1024 device are selected using the Clock Distribution Network. Four dedicated clock pins (Y0, Y1, Y2 and Y3) are brought into the distribution network, and five clock outputs (CLK 0, CLK 1, CLK 2, IOCLK 0 and IOCLK 1) are provided to route clocks to the GLBs and I/O cells. The Clock Distribution Network can also be driven from a special clock GLB (B4 on the ispLSI 1024 device). The logic of this GLB allows the user to create an internal clock from a combination of internal signals within the device.





Absolute Maximum Ratings 1

Supply Voltage V_{CC} -0.5 to +7.0V Input Voltage Applied -2.5 to V_{CC} +1.0V Off-State Output Voltage Applied -2.5 to V_{CC} +1.0V Storage Temperature -65 to 150°C Case Temp. with Power Applied -55 to 125°C

Max. Junction Temp. (T_J) with Power Applied ... 150°C

DC Recommended Operating Conditions

SYMBOL	PARAMETER		MIN.	MAX.	UNITS
		Commercial T _A = 0°C to +70°C	4.75	5.25	
V cc	Supply Voltage	Industrial $T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$	4.5	5.5	V
		Military/883 $T_c = -55^{\circ}\text{C to } +125^{\circ}\text{C}$	4.5	5.5	
VIL	Input Low Voltage		0	0.8	V
VIH	Input High Voltage		2.0	V cc + 1	V

Table 2- 0005Aisp w/mil.eps

Capacitance (T_A=25°C, f=1.0 MHz)

SYMBOL	PARAMETER				MAXIMUM ¹	UNITS	TEST CONDITIONS
C ₁	Dedicated Input Capacita		nmercial/Ir	ndustrial	8	pf	V _{CC} =5.0V, V _{IN} =2.0V
	Dedicated input Gapacita	Milit	tary		10	pf	V _{CC} =5.0V, V _{IN} =2.0V
C ₂	I/O and Clock Capacitano	е		·	10	pf	V _{CC} =5.0V, V _{I/O} , V _Y =2.0V

^{1.} Guaranteed but not 100% tested.

Table 2- 0006

Data Retention Specifications

PARAMETER	MINIMUM	MAXIMUM	UNITS
Data Retention	20	_	Years
Erase/Reprogram Cycles	10000	_	Cycles

Table 2- 0008B

^{1.} Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).



Switching Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise and Fall Time	≤ 3ns 10% to 90%
Input Timing Reference Levels	1.5V
Output Timing Reference Levels	1.5V
Output Load	See figure 2

3-state levels are measured 0.5V from steady-state active level.

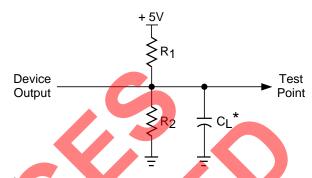
Table 2- 0003

Output Load Conditions (see figure 2)

Tes	t Condition	R1	R2	CL
Α		470Ω	390Ω	35pF
В	Active High	∞	390Ω	35pF
	Active Low	470Ω	390Ω	35pF
С	Active High to Z at V _{OH} - 0.5V	∞	390Ω	5pF
	Active Low to Z	470Ω	390Ω	5pF
	at V _{OL} + 0.5V			

Table 2- 0004A

Figure 2. Test Load



*CL includes Test Fixture and Probe Capacitance.

DC Electrical Characteristics

Over Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.3	MAX.	UNITS
V OL	Output Low Voltage	I _{OL} =8 mA	_	_	0.4	V
V OH	Output High Voltage	I _{OH} =-4 mA	2.4	_	-	V
lıL	Input or I/O Low Leakage Current	$0V \le V_{IN} \le V_{IL} (MAX.)$	_	_	-10	μΑ
Iн	Input or I/O High Leakage Current	$3.5V \le V_{IN} \le V_{CC}$	_	_	10	μΑ
IL-isp	isp Input Low Leakage Current	$0V \le V_{IN} \le V_{IL}$ (MAX.)	_	_	-150	μΑ
IIL-PU	I/O Active Pull-Up Current	$0V \le V_{IN} \le V_{IL}$	_	_	-150	μΑ
los1	Output Short Circuit Current	$V_{CC} = 5V$, $V_{OUT} = 0.5V$	_	_	-200	mA
ICC ^{2,4}	Operating Power Supply Current	$V_{IL} = 0.5V, V_{IH} = 3.0V$ Commercial	_	130	190	mA
		$f_{TOGGLE} = 1 \text{ MHz}$ Industrial/Military	_	135	215	mA

- 1. One output at a time for a maximum duration of one second. V_{out} = 0.5V was selected to avoid test problems by tester ground degradation. Characterized but not 100% tested.
- 2. Measured using six 16-bit counters.
- 3. Typical values are at $V_{cc} = 5V$ and $T_A = 25$ °C.
- Maximum I_{CC} varies widely with specific device configuration and operating frequency. Refer to the Power Consumption section of this datasheet and Thermal Management section of the Lattice Semiconductor Data Book and CD-ROM to estimate maximum I_{CC}.



External Timing Parameters

Over Recommended Operating Conditions

PARAMETER	METER TEST 5 #2 DESCRIPTION1		-9	90	-8	30	-6	60	UNITS	
ANAMETER	COND.	"	200Kii HON		MAX.	MIN.	MAX.	MIN.	MAX.	0.4.10
t pd1	Α	1	Data Propagation Delay, 4PT bypass, ORP bypass	_	12	_	15	_	20	ns
t pd2	Α	2	Data Propagation Delay, Worst Case Path	_	17	_	20	_	25	ns
f max (Int.)	Α	3	Clock Frequency with Internal Feedback ³	90.9		80	_	60	_	MHz
f max (Ext.)	-	4	Clock Frequency with External Feedback $(\frac{1}{t su2 + tco1})$	58.8		50	_	38	_	MHz
f max (Tog.)	-	5	Clock Frequency, Max Toggle ⁴	125	-	100	_	83	7	MHz
t su1	_	6	GLB Reg. Setup Time before Clock, 4PT bypass	6		7		9	-	ns
t co1	Α	7	GLB Reg. Clock to Output Delay, ORP bypass		8	-	10	7	13	ns
t h1	-	8	GLB Reg. Hold Time after Clock, 4 PT bypass	0	-	0	-	0	-	ns
t su2	-	9	GLB Reg. Setup Time before Clock	9	_	10	1-7	13	-	ns
t co2	-	10	GLB Reg. Clock to Output Delay	_	10	-	12	1	16	ns
t h2	-	11	GLB Reg. Hold Time after Clock	0		0	-	0	_	ns
t r1	Α	12	Ext. Reset Pin to Output Delay	-4	15	-	17	_	22.5	ns
trw1	-	13	Ext. Reset Pulse Duration	10	-	10	-	13	_	ns
t en	В	14	Input to Output Enable	1	15	_	18	-	24	ns
t dis	С	15	Input to Output Disable	-	15	_	18	_	24	ns
t wh	-	16	Ext. Sync. Clock Pulse Duration, High		_	5	_	6	_	ns
twl	-	17	Ext. Sync. Clock Pulse Duration, Low		_	5	-	6	_	ns
t su5	_	18	I/O Reg. Setup Time before Ext. Sync. Clock (Y2, Y3)	2	_	2	_	2.5	_	ns
t h5	ı	19	I/O Reg. Hold Time after Ext. Sync. Clock (Y2, Y3)	6.5	_	6.5	_	8.5	_	ns

Table 2-0030-24/90,80,60C

- 1. Unless noted otherwise, all parameters use a GRP load of 4 GLBs, 20 PTXOR path, ORP and Y0 clock.
- 2. Refer to Timing Model in this data sheet for further details.
- 3. Standard 16-Bit loadable counter using GRP feedback.
- 4. fmax (Toggle) may be less than 1/(twh + twl). This is to allow for a clock duty cycle of other than 50%.
- 5. Reference Switching Test Conditions Section.



Internal Timing Parameters¹

DADAMETED	# ² DESCRIPTION		-9	90	-80		-60		UNITS
PARAMETER # ²		DESCRIPTION		MAX.	MIN.	MAX.	MIN.	MAX.	UNITS
Inputs								11	
tiobp	20	I/O Register Bypass	_	1.6	_	2.0	_	2.7	ns
t iolat	21	I/O Latch Delay	_	2.4	_	3.0	_	4.0	ns
t iosu	22	I/O Register Setup Time before Clock	4.8	-	5.5	_	7.3	_	ns
t ioh	23	I/O Register Hold Time after Clock	2.1		1.0	_	1.3	_	ns
tioco	24	I/O Register Clock to Out Delay	-	2.4		3.0	-	4.0	ns
t ior	25	I/O Register Reset to Out Delay	7	2.8	_	2.5	ø	3.3	ns
t din	26	Dedicated Input Delay	-	3.2	_	4.0	4	5.3	ns
GRP									
t grp1	27	GRP Delay, 1 GLB Load	-	1.2	-	1.5	-	2.0	ns
t grp4	28	GRP Delay, 4 GLB Loads	_	1.6	_	2.0	_	2.7	ns
t grp8	29	GRP Delay, 8 GLB Loads	-	2.4	-	3.0	_	4.0	ns
t grp12	30	GRP Delay, 12 GLB Loads	_	3.0		3.8	_	5.0	ns
t grp16	31	GRP Delay, 16 GLB Loads	-	3.6	-	4.5	_	6.0	ns
t grp24	32	GRP Delay, 24 GLB Loads	-	5.0	_	6.3	_	8.3	ns
GLB					-			•	
t 4ptbp	33	4 Product Term Bypass Path Delay	-	5.2	_	6.5	_	8.6	ns
t 1ptxor	34	1 Product Term/XOR Path Delay	_	5.7	_	7.0	_	9.3	ns
t 20ptxor	35	20 Product Term/XOR Path Delay	_	7.0	_	8.0	_	10.6	ns
t xoradj	36	XOR Adjacent Path Delay ³	_	8.2	_	9.5	_	12.7	ns
t gbp	37	GLB Register Bypass Delay	_	8.0	_	1.0	_	1.3	ns
t gsu	38	GLB Register Setup Time before Clock	1.2	_	1.0	_	1.3	_	ns
t gh	39	GLB Register Hold Time after Clock	3.6	-	4.5	_	6.0	_	ns
t gco	40	GLB Register Clock to Output Delay	_	1.6	_	2.0	_	2.7	ns
t gr	41	GLB Register Reset to Output Delay	_	2.0	_	2.5	_	3.3	ns
t ptre	42	GLB Product Term Reset to Register Delay	_	8.0	_	10.0	_	13.3	ns
t ptoe	43	GLB Product Term Output Enable to I/O Cell Delay	_	7.8	_	9.0	_	12.0	ns
t ptck	44	GLB Product Term Clock Delay	2.8	6.0	3.5	7.5	4.6	9.9	ns
ORP									
t orp	45	ORP Delay	_	2.4	_	2.5	_	3.3	ns
t orpbp	46	ORP Bypass Delay	_	0.4	_	0.5	_	0.7	ns

Internal Timing Parameters are not tested and are for reference only.
 Refer to Timing Model in this data sheet for further details.

^{3.} The XOR Adjacent path can only be used by Hard Macros.



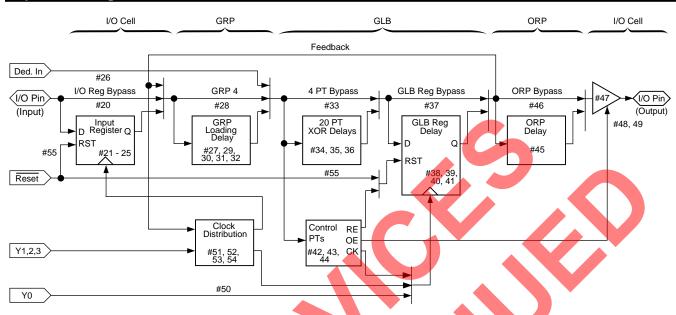
Internal Timing Parameters¹

PARAMETER	# ²	DESCRIPTION	-6	90	-8	80	-6	60	UNITS
PARAMETER	#	DESCRIPTION	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	UNITS
Outputs									
t ob	47	Output Buffer Delay	_	2.4	_	3.0	_	4.0	ns
t oen	48	I/O Cell OE to Output Enabled	_	4.0	-	5.0	_	6.7	ns
todis	49	I/O Cell OE to Output Disabled	-	4.0		5.0	_	6.7	ns
Clocks									
t gy0	50	Clock Delay, Y0 to Global GLB Clock Line (Ref. clock)	3.6	3.6	4.5	4.5	6.0	6.0	ns
t gy1/2	51	Clock Delay, Y1 or Y2 to Global GLB Clock Line	2.8	4.4	3.5	5.5	4.6	7.3	ns
t gcp	52	Clock Delay, Clock GLB to Global GLB Clock Line	0.8	4.0	1.0	5.0	1.3	6.6	ns
t ioy2/3	53	Clock Delay, Y2 or Y3 to I/O Cell Global Clock Line	2.8	4.4	3.5	5.5	4.6	7.3	ns
t iocp	54	Clock Delay, Clock GLB to I/O Cell Global Clock Line		4.0	1.0	5.0	1.3	6.6	ns
Global Re	set								
t gr	55	Global Reset to GLB and I/O Registers	-	8.2	-	9.0	_	12.0	ns

Internal Timing Parameters are not tested and are for reference only.
 Refer to Timing Model in this data sheet for further details.



ispLSI Timing Model



Derivations of tsu, th and tco from the Product Term Clock¹

```
tsu = Logic + Reg su - Clock (min)

= (tiobp + tgrp4 + t20ptxor) + (tgsu) - (tiobp + tgrp4 + tptck(min))

= (#20 + #28 + #35) + (#38) - (#20 + #28 + #44)

5.5 ns = (2.0 + 2.0 + 8.0) + (1.0) - (2.0 + 2.0 + 3.5)

th = Clock (max) + Reg h - Logic

= (tiobp + tgrp4 + tptck(max)) + (tgh) - (tiobp + tgrp4 + t20ptxor)

= (#20 + #28 + #44) + (#39) - (#20 + #28 + #35)

4.0 ns = (2.0 + 2.0 + 7.5) + (4.5) - (2.0 + 2.0 + 8.0)

tco = Clock (max) + Reg co + Output

= (tiobp + tgrp4 + tptck(max)) + (tgco) + (torp + tob)

= (#20 + #28 + #44) + (#40) + (#45 + #47)

19.0 ns = (2.0 + 2.0 + 7.5) + (2.0) + (2.5 + 3.0)
```

Derivations of tsu, th and tco from the Clock GLB¹

```
tsu = Logic + Reg su - Clock (min)

= (tiobp + tgrp4 + t20ptxor) + (tgsu) - (tgy0(min) + tgco + tgcp(min))

= (#20 + #28 + #35) + (#38) - (#50 + #40 + #52)

5.5 ns = (2.0 + 2.0 + 8.0) + (1.0) - (4.5 + 2.0 + 1.0)

th = Clock (max) + Reg h - Logic

= (tgy0(max) + tgco + tgcp(max)) + (tgh) - (tiobp + tgrp4 + t20ptxor)

= (#50 + #40 + #52) + (#39) - (#20 + #28 + #35)

4.0 ns = (4.5 + 2.0 + 5.0) + (4.5) - (2.0 + 2.0 + 8.0)

tco = Clock (max) + Reg co + Output

= (tgy0(max) + tgco + tgcp(max)) + (tgco) + (torp + tob)

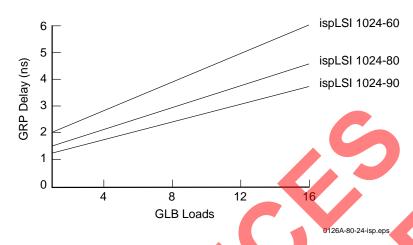
= (#50 + #40 + #52) + (#40) + (#45 + #47)

19.0 ns = (4.5 + 2.0 + 5.0) + (2.0) + (2.5 + 3.0)
```

1. Calculations are based upon timing specifications for the ispLSI 1024-80.



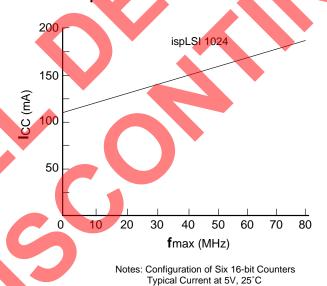
Maximum GRP Delay vs GLB Loads



Power Consumption

Power consumption in the ispLSI 1024 device depends ure 3 shows the relationship between power and operation two primary factors: the speed at which the device is operating, and the number of Product Terms used. Fig.

Figure 3. Typical Device Power Consumption vs fmax



ICC can be estimated for the ispLSI 1024 using the following equation:

I_{CC} = 42 + (# of PTs * 0.45) + (# of nets * Max. freq * 0.008) where: # of PTs = Number of Product Terms used in design

of nets = Number of Signals used in device

Max. freq = Highest Clock Frequency to the device

The ICC estimate is based on typical conditions (VCC = 5.0V, room temperature) and an assumption of 2 GLB loads on average exists. These values are for estimates only. Since the value of ICC is sensitive to operating conditions and the program in the device, the actual ICC should be verified.

0127A-24-80-isp



Pin Description

NAME	PLCC and JLCC PIN NUMBERS	TQFP PIN NUMBERS	DESCRIPTION
I/O 0 - I/O 3 I/O 4 - I/O 7 I/O 8 - I/O 11 I/O 12 - I/O 15 I/O 16 - I/O 19 I/O 20 - I/O 23 I/O 24 - I/O 27 I/O 28 - I/O 31 I/O 32 - I/O 35 I/O 36 - I/O 39 I/O 40 - I/O 43 I/O 44 - I/O 47	22, 23, 24, 25, 26, 27, 28, 29, 30, 31, 32, 33, 37, 38, 39, 40, 41, 42, 43, 44, 45, 46, 47, 48, 56, 57, 58, 59, 60, 61, 62, 63, 64, 65, 66, 67, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14	19, 20, 21, 22, 23, 28, 29, 30, 31, 32, 33, 34, 42, 43, 44, 45, 46, 47, 48, 53, 54, 55, 56, 57, 69, 70, 71, 72, 73, 78, 79, 80, 81, 82, 83, 84, 92, 93, 94, 95, 96, 97, 98, 3, 4, 5, 6, 7	Input/Output Pins - These are the general purpose I/O pins used by the logic array.
IN 4 - IN 5	2, 15	91, 8	Input - These pins are dedicated input pins to the device.
ispEN	19	16	Input - Dedicated in-system programming enable input pin. This pin is brought low to enable the programming mode. The MODE, SDI, SDO and SCLK options become active.
SDI/IN 0 ¹	21	18	Input - This pin performs two functions. When ispEN is logic low, it functions as an input pin to load programming data into the device. SDI/IN 0 is also used as one of the two control pins for the isp state machine. It is a dedicated input pin when ispEN is logic high.
MODE/IN 3 ¹	55	68	Input - This pin performs two functions. When ispEN is logic low, it functions as pin to control the operation of the isp state machine. It is a dedicated input pin when ispEN is logic high.
SDO/IN 1 ¹	34	35	Output/Input - This pin performs two functions. When ispEN is logic low, it functions as an output pin to read serial shift register data. It is a dedicated input pin when ispEN is logic high.
SCLK/IN 2 ¹	49	58	Input - This pin performs two functions. When ispEN is logic low, it functions as a clock pin for the Serial Shift Register. It is a dedicated input pin when ispEN is logic high.
NC ²	_	1, 2, 12, 13, 24, 25, 26, 27,	No Connect
		38, 39, 49, 50, 51, 52, 63 64, 74, 75, 76, 77	
		87, 88, 99, 100	
RESET	20	17	Active Low (0) Reset pin which resets all of the GLB and I/O registers in the device.
Y0	16	9	Dedicated Clock input. This clock input is connected to one of the clock inputs of all of the GLBs on the device.
Y1	54	67	Dedicated Clock input. This clock input is brought into the clock distribution network, and can optionally be routed to any GLB on the device.
Y2	51	60	Dedicated Clock input. This clock input is brought into the clock distribution network, and can optionally be routed to any GLB and/or any I/O cell on the device.
Y3	50	59	Dedicated Clock input. This clock input is brought into the clock distribution network, and can optionally be routed to any I/O cell on the device.
GND	1, 18, 35, 52	14, 15, 36, 37, 61, 62, 89, 90	Ground (GND)
VCC	17, 36, 53, 68	10, 11, 40, 41, 65, 66, 85, 86	V _{CC}

^{1.} Pins have dual function capability.

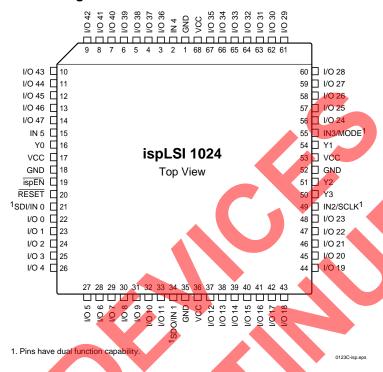
Table 2 - 0002C-24

^{2.} NC pins are not to be connected to any active signals, Vcc or GND.

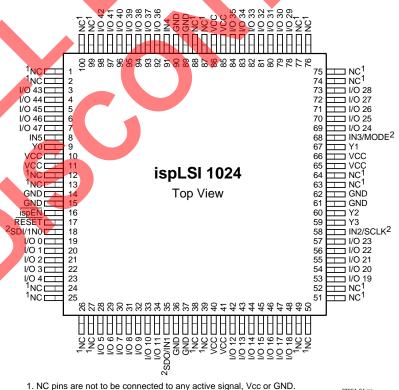


Pin Configuration

ispLSI 1024 68-Pin PLCC Pinout Diagram



ispLSI 1024 100-Pin TQFP Pinout Diagram

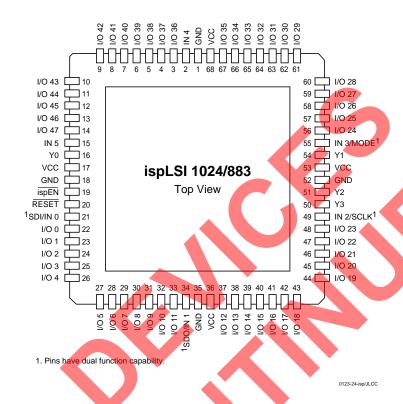


2. Pins have dual function capability.



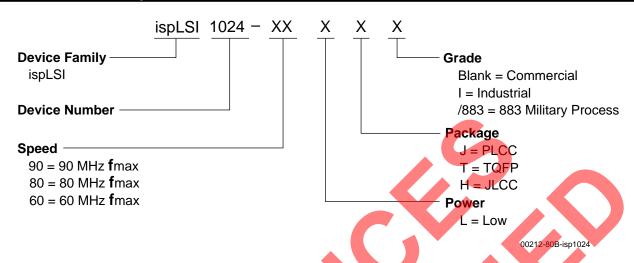
Pin Configuration

ispLSI 1024 68-Pin JLCC Pinout Diagram





Part Number Description



Ordering Information

COMMERCIAL

Family	f max (MHz)	tpd (ns) Ordering Number		Package	
	90	12	ispLSI 1024-90LJ	68-Pin PLCC	
	90	12	ispLSI 1024-90LT	100-Pin TQFP	
ispLSI	80	15	ispLSI 1024-80LJ	68-Pin PLCC	
	80	15	ispLSI 1024-80LT	100-Pin TQFP	
	60	20	ispLSI 1024-60LJ	68-Pin PLCC	
	60	20	ispLSI 1024-60LT	100-Pin TQFP	

INDUSTRIAL

Family	f max (MHz)	tpd (ns)	Ordering Number	Package
ispLSI	60	20	ispLSI 1024-60LJI	68-Pin PLCC
	60	20	ispLSI 1024-60LTI	100-Pin TQFP

MILITARY/883

Family	fmax (I	MHz)	t pd (ns)	Ordering Number	SMD#	Package
ispLSI	60		20	ispLSI 1024-60LH/883	5962-9476101MXC	68-Pin JLCC

Note: Lattice Semiconductor recognizes the trend in military device procurement towards using SMD compliant devices, as such, ordering by this number is recommended.

Table 2-0041A-24-isp